			Search Notes			
¢-	•	-%				

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/397,811	HATOH ET AL.		
Examiner	Art Unit		
Julian Mercado	1745		

SEARCHED							
Class	Subclass	Date	Examiner				
·							
· - · · · ·							

INT	INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner				
			 				
		ı					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated Search (a Habel)	4/8/36			